

Silicon Carbide Enhancement Mode MOSFET

Features

- High blocking voltage with low $R_{DS(on)}$
- High frequency operation with low Capacitance
- Simple to drive with -4V/+18V gate
- Robust body diode with low Q_{rr}
- 100% Avalanche Tested

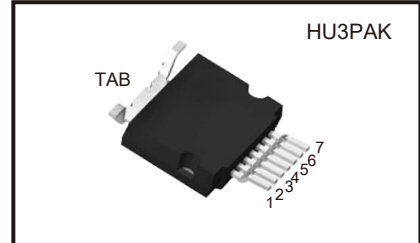
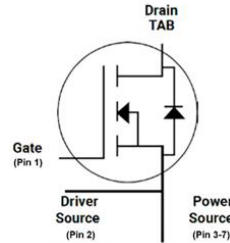
Benefits

- Superior robustness and system reliability
- Higher system efficiency
- Easier paralleling without thermal runaway
- Capable of high temperature application
- Faster and more efficient switching

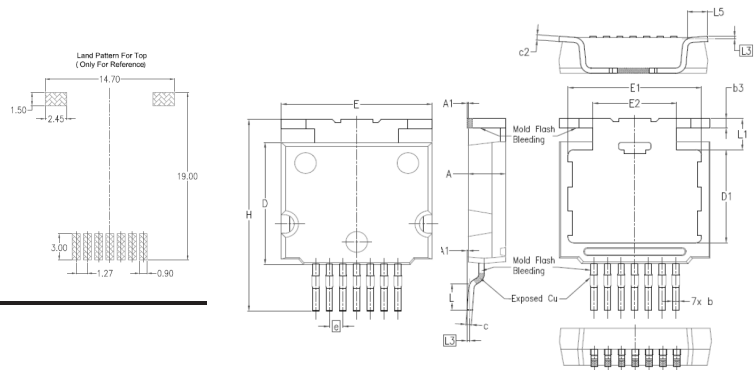
Applications

- EV/HEV charging station
- Energy storage and Battery charging
- High voltage DC-DC converters
- Solar / Wind Inverters
- UPS and PFC

V_{DSS}	1200V
$I_D(@25^{\circ}C)$	128A
$R_{DS(ON) typ.}$	17m Ω



Package Dimensions



Absolute Maximum Ratings

($T_C = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage $V_{GS}=0V$ $I_D=100\mu A$	V_{DS}	1200	V
Gate-Source Voltage (dynamic) AC ($f>1$ Hz, duty cycle<1%, pulse width<200ns)	V_{GS}	-9/+22	V
Gate-Source Voltage (static)	$V_{GS(op)}$	-4/+18	V
Drain Current-Continuous $V_{GS}=18V@ T_C=25^{\circ}C$ $V_{GS}=18V@ T_C=100^{\circ}C$	I_D	128 90	A
Pulse Drain Current	$I_{D,pulse}$	260	A
Power Dissipation	P_D	555	W
Storage Temperature Range	T_{STG}	-55 to +175	$^{\circ}C$
Operating Junction Temperature Range	T_J	-55 to +175	$^{\circ}C$
Soldering Temperature	T_L	260	$^{\circ}C$
Avalanche Capability, single pulse * $V_{DD}=100V$ $V_{GS}=10V$ $L=2mH$	I_{AV}	47	A
Avalanche Capability, single pulse** $V_{DD}=100V$ $V_{GS}=10V$ $L=2mH$	E_{AV}	2298	mJ

* 100% tested in 60% rating

** 100% tested in 36% rating

SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	3.40	3.50	3.60
A1	0.00	0.10	0.25
b	0.50	0.60	0.70
b3	0.80	0.90	1.00
c	0.40	0.50	0.60
c2	0.40	0.50	0.60
D	11.70	11.80	11.90
D1	8.80	9.00	9.10
E	13.90	14.00	14.10
E1	12.30	12.40	12.50
E2	7.75	7.80	7.85
e	1.27 BSC		
H	18.00	18.50	19.00
L	2.30	2.50	2.75
L1	—	3.05	—
L3	—	0.26	—
L5	1.70	1.90	2.15

Electrical Characteristics @ $T_c = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions		Min.	Typ.	Max.	Unit
OFF Characteristics							
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V , I _D =0.1mA		1200	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =1200V V _{GS} =0V	T _J =25℃	-	0.5	100	μA
			T _J =175℃	-	5	200	
Gate-Source Leakage Current	I _{GSS}	V _{GS} =18V , V _{DS} =0V		-	5	100	nA
		V _{GS} =-4V , V _{DS} =0V		-100	-5	-	
ON Characteristics							
Gate Threshold Voltage ***	V _{GS(th)}	V _{DS} = V _{GS} , I _D =20mA	T _J =25℃	2.2	3.0	4.2	V
			T _J =175℃	-	2.2	-	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} =18V , I _D =50A	T _J =25℃	-	17	24	mΩ
			T _J =175℃	-	33	-	
Transconductance	g _{fs}	V _{DS} =20V , I _D =50A	T _J =25℃	-	41	-	S
			T _J =175℃	-	39	-	
Internal Gate Resistance	R _{G(int.)}	f =1MHz , I _D =0A		-	1.3	-	Ω
Dynamic Characteristics							
Input Capacitance	C _{iss}	V _{DS} =1000V V _{GS} =0V f =100kHz V _{AC} =25mV		-	4400	-	pF
Output Capacitance	C _{oss}			-	170	-	
Reverse Transfer Capacitance	C _{rss}			-	15	-	
C _{oss} Stored Energy	E _{oss}			-	100	-	μJ
Turn-On Switching Energy	E _{on}	V _{DS} =800V , V _{GS} =-4/+18V I _D =50A , R _{G(ext)} =2.0Ω L =200μH		-	408	-	μJ
Turn-Off Switching Energy	E _{off}			-	105	-	
Switching Characteristics							
Turn-On Delay Time	t _{d(on)}	V _{DS} =800V , V _{GS} =-4/+18V I _D =50A , R _{G(ext)} =2.0Ω L =200μH		-	19	-	ns
Rise Time	t _r			-	23	-	
Turn-Off Delay Time	t _{d(off)}			-	40	-	
Fall Time	t _f			-	10	-	
Total Gate Charge	Q _g	V _{DS} =800V V _{GS} =-4/+18V I _D =50A		-	210	-	nC
Gate to Source Charge	Q _{gs}			-	55	-	
Gate to Drain Charge	Q _{gd}			-	80	-	
Body Diode Characteristics							
Inverse Diode Forward Voltage	V _{SD}	V _{GS} =0V , I _{SD} =40A	T _J =25℃	-	3.5	-	V
Inverse Diode Forward Voltage			T _J =175℃	-	3.25	-	V
Continuous Diode Forward Current	I _S	V _{GS} =0V , T _J =25℃		-	100	-	A
Reverse Recovery Time	T _{rr}	I _{SD} =50A , V _{GS} =-4V V _R =800V , R _{G(ext)} =20Ω dif/dt =1430A/μs L =200μH		-	25	-	ns
Reverse Recovery Charge	Q _{rr}			-	430	-	nC
Reverse Recovery Charge	I _{rrm}			-	31	-	A
Thermal Resistance							
Thermal Resistance, Junction-to-Case	Rθ _{Jc}			-	0.27	0.32	℃/W

*** Turn-off with -4V gate bias is highly recommended

Typical Performance

Fig 1. Output Characteristics, $T_J = 25^\circ\text{C}$

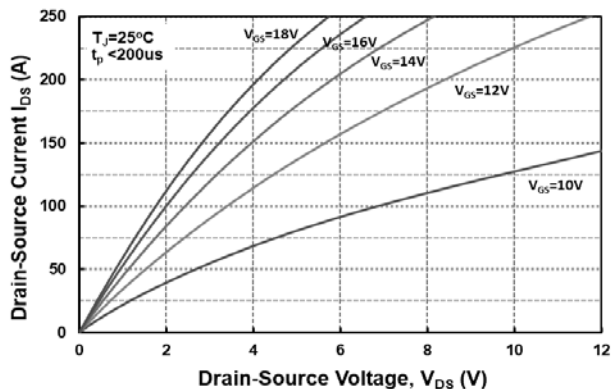


Fig 2. Output Characteristics, $T_J = 175^\circ\text{C}$

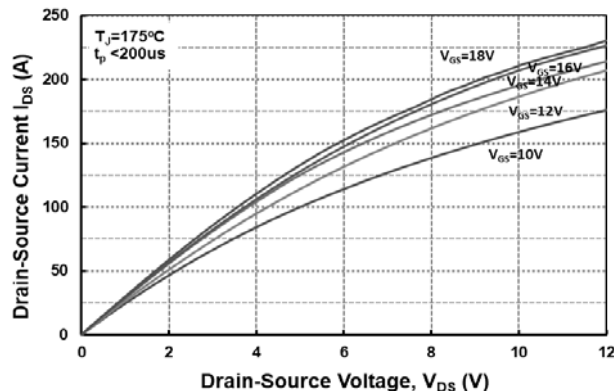


Fig 3. Output Characteristics, $T_J = -40^\circ\text{C}$

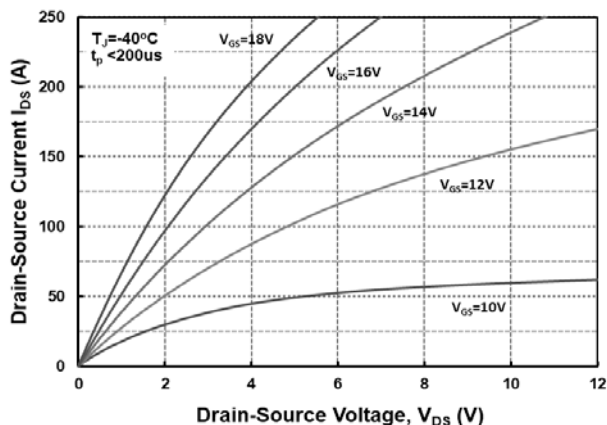


Fig 4. Threshold Voltage vs. Temperature

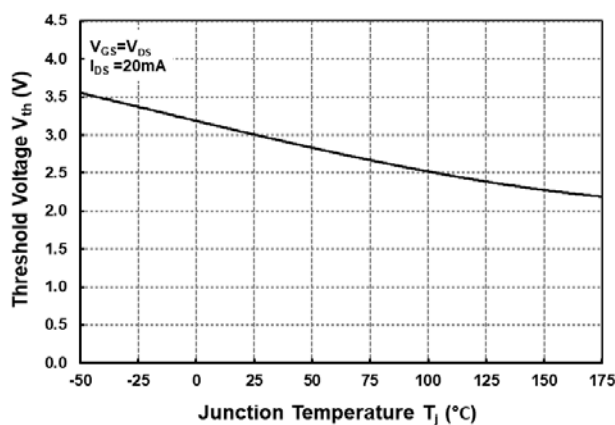


Fig 5. On-Resistance vs. Drain Current for Various Temperatures

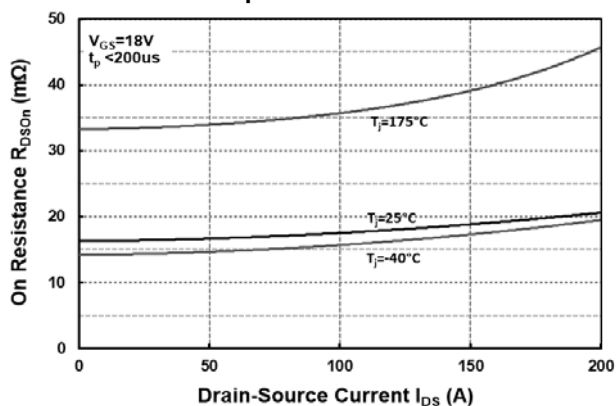
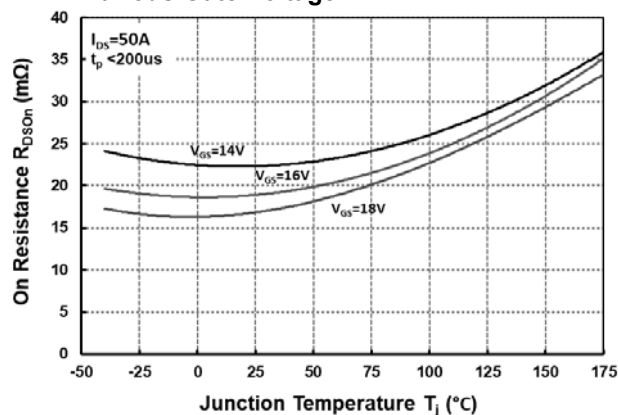


Fig 6. On-Resistance vs. Temperature for Various Gate Voltage



Typical Performance

Fig 7. Transfer Characteristic for Various Junction Temperatures

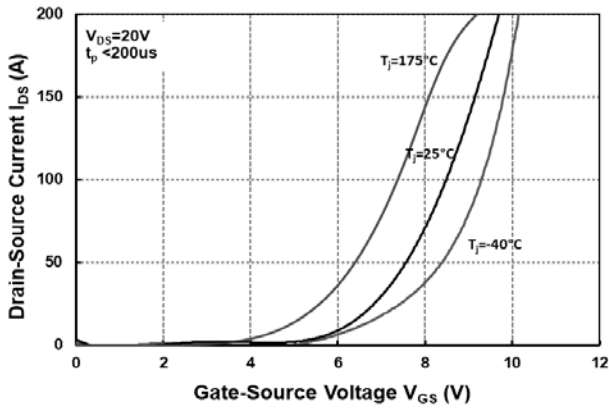


Fig 8. Body Diode Characteristics @ -40°C

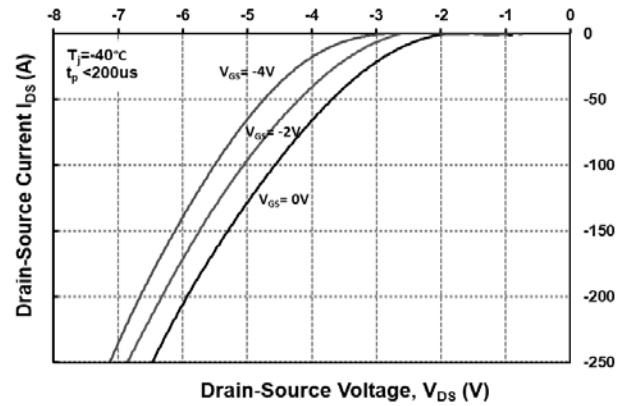


Fig 9. Body Diode Characteristics @ 25°C

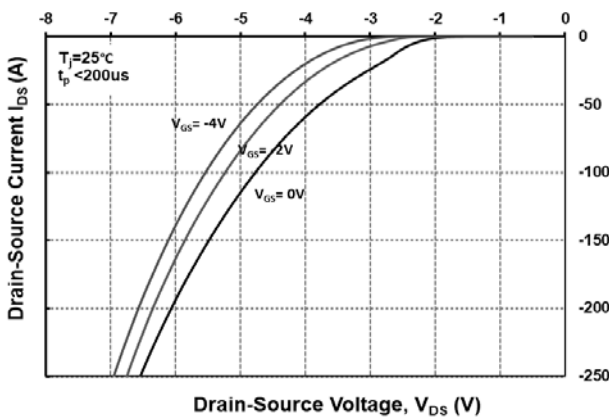


Fig 10. Body Diode Characteristics @ 175°C

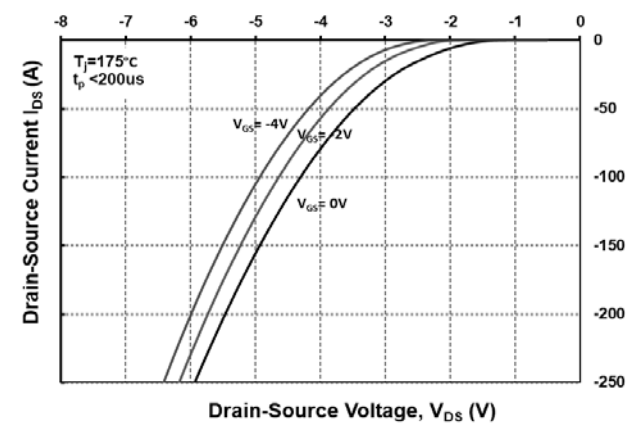


Fig 11. Gate Charge Characteristics

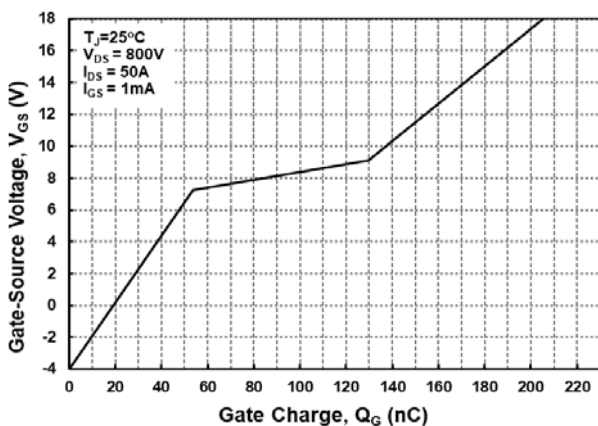
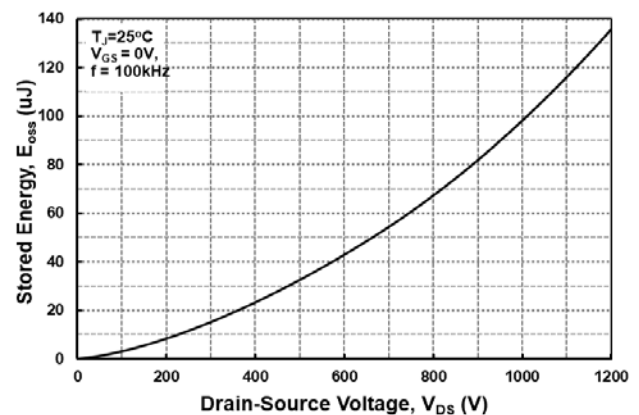


Fig 12. Output Capacitor Stored Energy



Typical Performance

Fig 13. 3rd Quadrant Characteristics @ -40°C

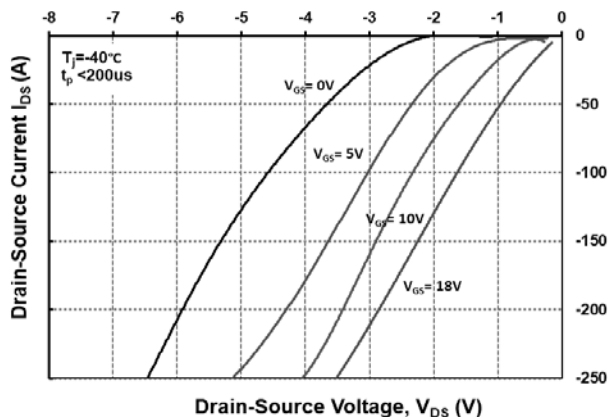


Fig 14. 3rd Quadrant Characteristics @ 25°C

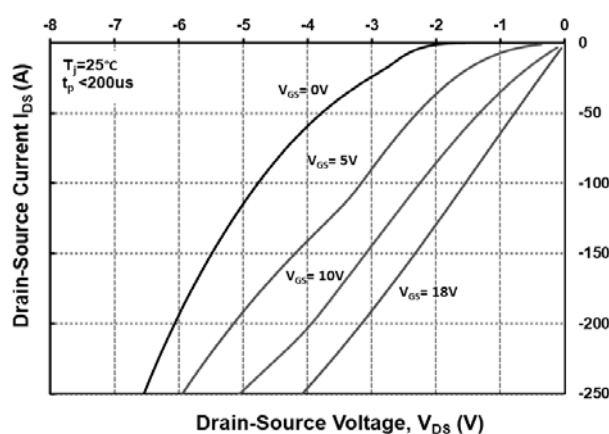


Fig 15. 3rd Quadrant Characteristics @ 175°C

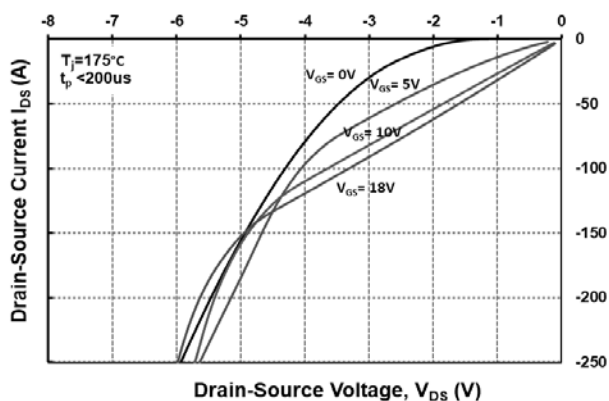


Fig 16. Safe Operating Area

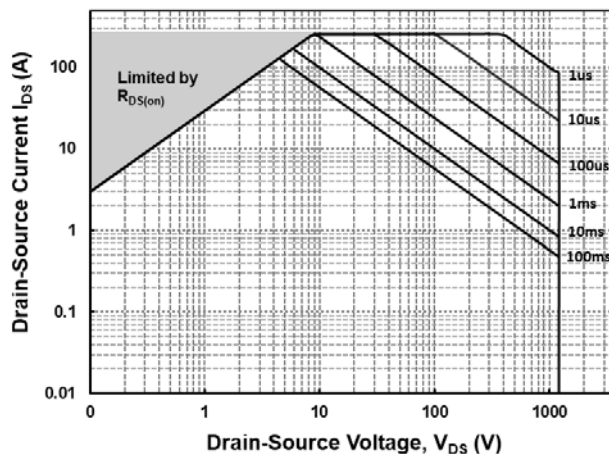


Fig 17. Capacitances vs. Drain-Source Voltage (0-200V)

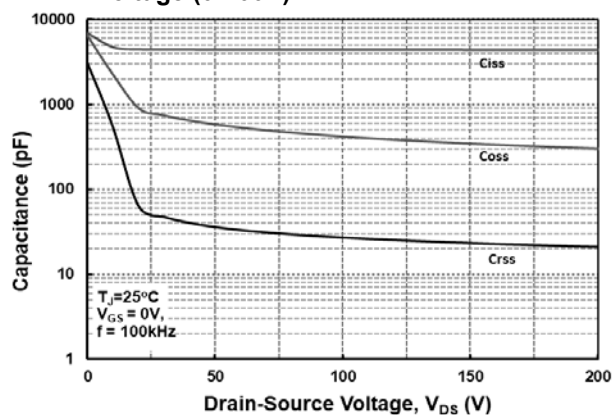
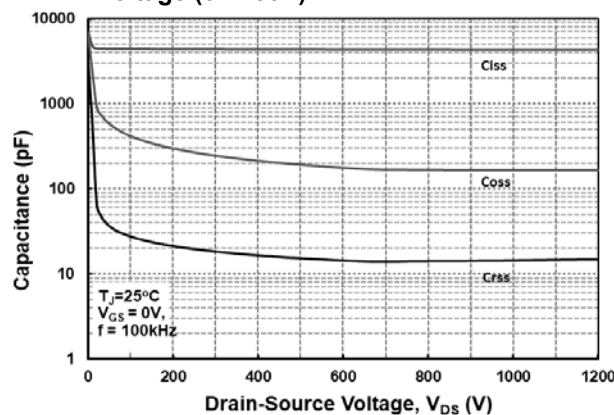


Fig 18. Capacitances vs. Drain-Source Voltage (0-1200V)



Typical Performance

Fig 19. Continuous Drain Current Derating vs. Case Temperature

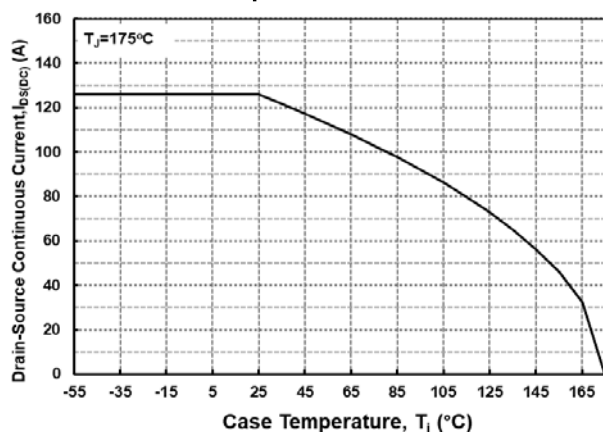


Fig 20. Maximum Power Dissipation Derating vs. Case Temperature

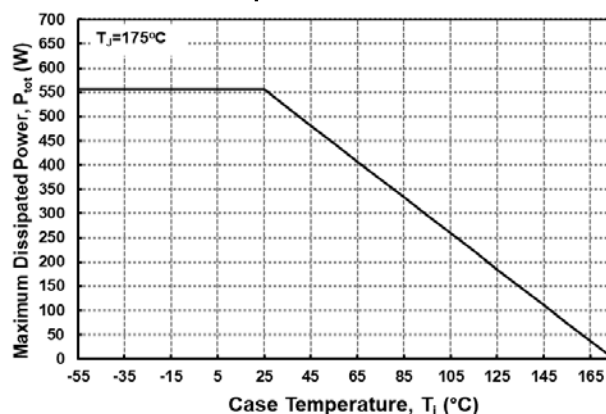


Fig 21. Clamped Inductive Switching Energy vs Drain Current ($V_{DD} = 800\text{V}$)

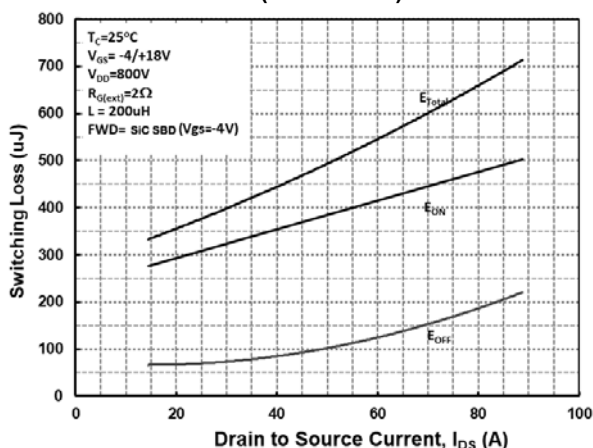


Fig 22. Clamped Inductive Switching Energy vs External Gate Resistor $R_{G(ext)}$

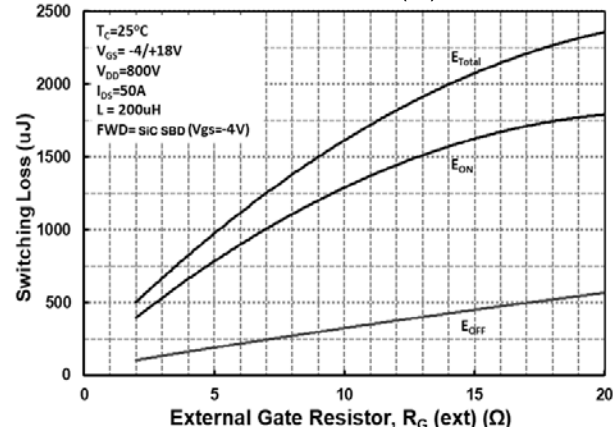


Fig 23. Switching Times vs Drain Current ($V_{DD} = 800\text{V}$)

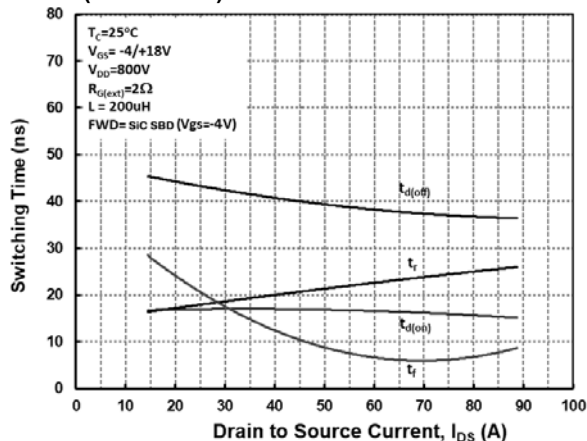
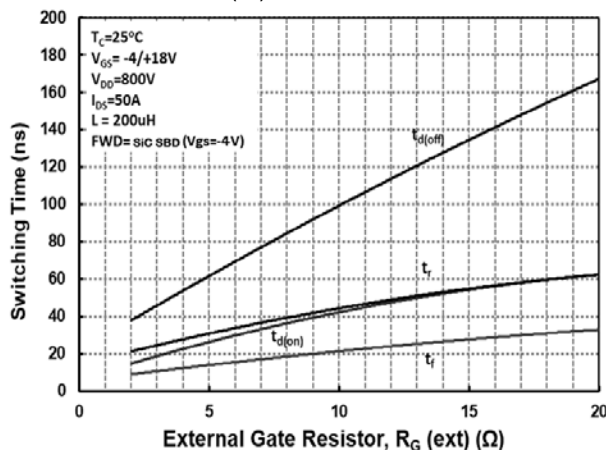
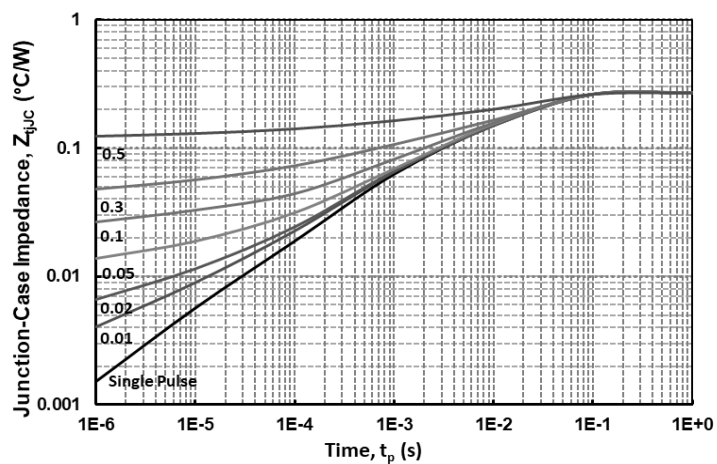


Fig 24. Switching Times vs External Gate Resistor $R_{G(ext)}$



Typical Performance

Fig 26. Transient Thermal Impedance
(Junction – Case)



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